

April 2001
PRELIMINARY

# FDP6021P/FDB6021P

## 20V P-Channel 1.8V Specified PowerTrench® MOSFET

### **General Description**

This P-Channel power MOSFET uses Fairchild's low voltage PowerTrench process. It has been optimized for power management applications.

## **Applications**

- · Battery management
- · Load switch
- Voltage regulator

### **Features**

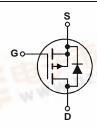
- -28 A, -20 V.  $R_{DS(ON)} = 30$  m $\Omega$  @  $V_{GS} = 4.5$  V  $R_{DS(ON)} = 40$  m $\Omega$  @  $V_{GS} = 2.5$  V  $R_{DS(ON)} = 65$  m $\Omega$  @  $V_{GS} = 1.8$  V
- Critical DC electrical parameters specified at elevated temperature
- High performance trench technology for extremely low R<sub>DS(ON)</sub>
- 175°C maximum junction temperature rating







TO-263AB FDB Series



Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
$V_{DSS}$	Drain-Source Voltage		-20	V
V <sub>GSS</sub>	Gate-Source Voltage		± 8	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1)	-28	Α
	- Pulsed	(Note 1)	-80	# (W)
P <sub>D</sub>	Total Power Dissipation @ T <sub>C</sub> = 25°C		37	W
	Derate above 25°C		0.25	W°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-65 to +175	°C

### Thermal Characteristics

R <sub>θJC</sub>	Thermal Resistance, Junction-to-Case	4	°C/W
R <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

Package Marking and Ordering Information

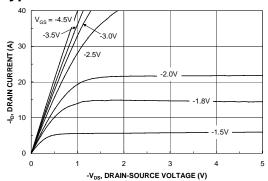
Device	ce Marking	Device	Reel Size	Tape width	Quantity
FD	P6021P	FDP6021P	Tube	n/a	45
FD	)B6021P	FDB6021P	13"	24mm	800 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics			ı	ı	·
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-20			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu A$ , Referenced to 25°C		-16		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V},  V_{GS} = 0 \text{ V}$			-1	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage, Forward	$V_{GS} = 8 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage, Reverse	$V_{GS} = -8 \text{ V}$ $V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.4	-0.7	-1.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \mu A$ , Referenced to $25^{\circ}C$		3		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$\begin{tabular}{lllllllllllllllllllllllllllllllllll$		24 31 50 30	30 40 65 42	mΩ
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = -4.5 \text{ V},  V_{DS} = -5 \text{ V}$	-40			Α
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5 \text{ V}, \qquad I_{D} = -14 \text{ A}$		33		S
Dynamic	Characteristics					
Ciss	Input Capacitance	$V_{DS} = -10 \text{ V},  V_{GS} = 0 \text{ V},$		1890		pF
Coss	Output Capacitance	f = 1.0 MHz		302		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	]		124		pF
Switchir	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = -10 \text{ V}, \qquad I_{D} = -1 \text{ A},$		13	23	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		10	20	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	7		80	128	ns
t <sub>f</sub>	Turn-Off Fall Time	1		50	80	ns
$Q_g$	Total Gate Charge	$V_{DS} = -10 \text{ V}, \qquad I_{D} = -14 \text{ A},$		20	28	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = -4.5 \text{ V}$		4		nC
$Q_{gd}$	Gate-Drain Charge			7		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source	e Diode Forward Current			-28	Α
$V_{SD}$	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_{S} = -14 \text{ A}$		-0.9	-1.3	V

#### Notes

- 1. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%
- 2. TO-220 package is supplied in tube / rail @ 45 pieces per rail.
- 3. Calculated continuous current based on maximum allowable junction temperature. Actual maximum continuous current limited by package constraints to 75A

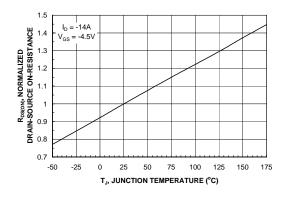
## **Typical Characteristics**



2.4 R<sub>DS(ON)</sub>, NORMALIZED DRAIN-SOURCE ON-RESISTANCE 2.2 V<sub>GS</sub> = -1.8V 2 -2.5V 1.2 -3.0V --3.5V 0.8 0 10 20 30 40 -I<sub>D</sub>, DRAIN CURRENT (A)

Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



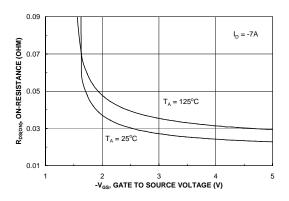
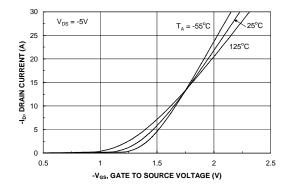


Figure 3. On-Resistance Variation withTemperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



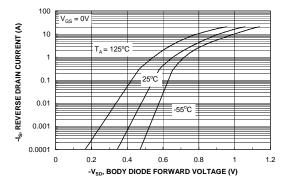
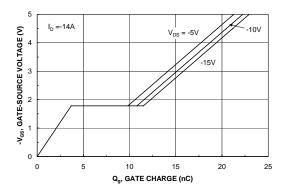


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

## **Typical Characteristics**



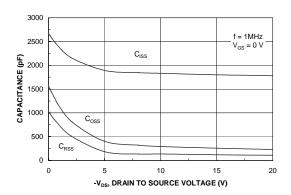


Figure 7. Gate Charge Characteristics.

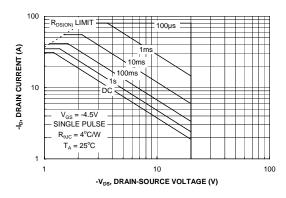


Figure 8. Capacitance Characteristics.

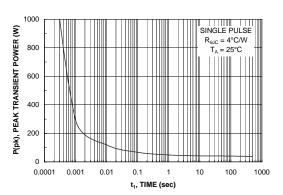


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

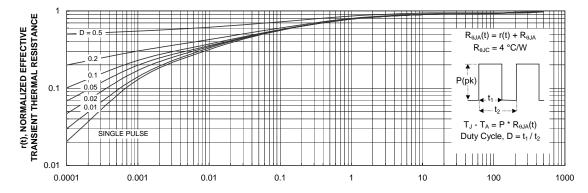


Figure 11. Transient Thermal Response Curve.

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